The JEOL JSM-7200F Scanning Electron Microscope: (https://www.jeol.co.jp/en/products/detail/JSM-7200F.html): "JSM-7200F has much higher spatial resolution than the conventional models at both high and low accelerating voltages by applying the technology used for "In-Lens SchottkyPlus", the electron optics equipped on our flagship-model, JSM-7800FPRIME, and by incorporating TTLS (Through-The-Lens System). The maximum probe current of 300 nA is also guaranteed because of the above-mentioned features. Thus, JSM-7200F is a next-generation multi-purpose FE-SEM that has capability of high-resolution observation, high throughput analysis, ease of use, and expandability."

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- The Parthenon, September 19th, 2018
- MU University Communications October 12th, 2018
- We Are Marshall Newsletter, October 17th, 2018